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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/864,309	05/25/2001	Shigeyuki Uzawa	862.C2239 2803	
5514	7590 02/26/2004	EXAMINER		
FITZPATRICK CELLA HARPER & SCINTO			JARRETT, RYAN A	
30 ROCKEFELLER PLAZA NEW YORK, NY 10112			ART UNIT	PAPER NUMBER
			2125	1/1
			DATE MAILED: 02/26/2004	4

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
	09/864,309	UZAWA ET AL.			
Office Action Summary	Examiner	Art Unit			
-	Ryan A. Jarrett	2125			
The MAILING DATE of this communication app					
P riod for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a reply within the statutory minimum of thirty (30) days will be considered timely. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).					
Status					
1)⊠ Responsive to communication(s) filed on <u>05 February 2004</u> .					
2a)⊠ This action is FINAL . 2b)□ This)⊠ This action is FINAL . 2b)□ This action is non-final.				
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims					
 4) Claim(s) 48-62 is/are pending in the application. 4a) Of the above claim(s) is/are withdrawn from consideration. 5) Claim(s) is/are allowed. 6) Claim(s) 48-62 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/or election requirement. 					
Application Papers 9)☐ The specification is objected to by the Examiner.					
10) The drawing(s) filed on is/are: a) acce		Examiner.			
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).					
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).					
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.					
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s)					
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date S Patent and Trademark Office					

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DETAILED ACTION

Response to Arguments

1. Applicant's arguments filed 9/4/03 have been fully considered but they are not persuasive. Applicant argues that Ueda et al. does not teach the features of the port section recited in claim 48, which include a vacuum mechanism for creating a vacuum inside of the port section and a supply mechanism for supplying an inert gas into the inside of the port section. However, Fig. 12 clearly depicts supply mechanism 410, 411 for supplying a gas into the inside of the port section 403 and a vacuum mechanism 417 for creating a vacuum inside of the port section 403.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 3. Claims 48-62 are rejected under 35 U.S.C. 102(e) as being anticipated by Ueda et al. U.S. Patent No. 6,319,322. Ueda et al. discloses an exposure apparatus for exposing a wafer to a pattern, said apparatus comprising: a chamber in which an atmosphere is conditioned to be different from an atmosphere in another apparatus outside of said exposure apparatus and the wafer is exposed to the pattern; and a port section through which the wafer is transferred between said chamber and the other

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apparatus, said port section having a load-lock mechanism including a vacuum mechanism for creating a vacuum inside of said port section and a supply mechanism for supplying an inert gas into the inside of said port section;

wherein said exposure apparatus includes a plurality of said port sections; wherein said port sections include a first port section for loading the wafer and a second port section for unloading the wafer; further comprising an interface section for stocking a wafer between said port section and the other apparatus; wherein said interface section includes a load-lock mechanism; wherein said interface section is shared by a plurality of said port sections; wherein the other apparatus includes a coating/developing system; wherein said port section includes a temperature control mechanism for controlling a temperature of the wafer; wherein said temperature control mechanism includes at least one of a heater and a cooler; wherein said load-lock mechanism and said temperature control mechanism operate in parallel with each other; wherein said chamber includes a temperature control mechanism for controlling a temperature of the wafer; wherein an ambient atmosphere of said temperature control mechanism is conditioned to be different from another atmosphere in said chamber;

a device manufacturing system comprising: an exposure apparatus defined in claim 48; and another apparatus which performs for a wafer at least one of a pre-process and a post-process with respect to an exposure process to be performed by said exposure apparatus; a device manufacturing method comprising a step of exposing a wafer to a pattern using an exposure apparatus defined in claim 48; a device manufacturing method comprising a step of processing a wafer using a device

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manufacturing system as defined in claim 60 (e.g. col. 1 line 32 – col. 2 line 43, col. 5 lines 1-53, col. 6 lines 33-67, col. 7 lines 20-40, col. 8 lines 15-67, col. 9 line 44 – col. 10 line 35, col. 11 lines 6-14, col. 12 lines 6-11, Fig. 12).

Conclusion

4. All claims are drawn to the same invention claimed in the application prior to the entry of the submission under 37 CFR 1.114 and could have been finally rejected on the grounds and art of record in the next Office action if they had been entered in the application prior to entry under 37 CFR 1.114. Accordingly, **THIS ACTION IS MADE FINAL** even though it is a first action after the filing of a request for continued examination and the submission under 37 CFR 1.114. See MPEP § 706.07(b). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

5. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ryan A. Jarrett whose telephone number is (703) 308-4739. The examiner can normally be reached on 10:00-6:30 M-F.

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If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Leo Picard can be reached on (703) 308-0538. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

2/24/03

Ryan A. Jarrett Examiner Art Unit 2125

LEO PICARD SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100

J. P. Pril